## Features

- Fast read access time 45ns
- Low-power CMOS operation
  - 100µA max standby
  - 20mA max active at 5MHz
- JEDEC standard packages
  - 28-lead PDIP
  - 32-lead PLCC
- 5V ± 10% supply
- High-reliability CMOS technology
  - 2,000V ESD protection
  - 200mA latchup immunity
- Rapid programming algorithm 100µs/byte (typical)
- CMOS- and TTL-compatible inputs and outputs
- Integrated product identification code
- Industrial and automotive temperature ranges
- Green (Pb/halide-free) packaging option

## 1. Description

The Atmel<sup>®</sup> AT27C512R is a low-power, high-performance, 524,288-bit, one-time programmable, read-only memory (OTP EPROM) organized as 64K by 8 bits. It requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 45ns, eliminating the need for speed reducing WAIT states on high-performance microprocessor systems.

The Atmel scaled CMOS technology provides high speed, lower active power consumption, and significantly faster programming. Power consumption is typically only 8mA in active mode and less than  $10\mu$ A in standby mode.

The AT27C512R is available in a choice of industry-standard, JEDEC-approved, one-time programmable (OTP) PDIP and PLCC packages. All devices feature two-line control ( $\overline{CE}$ ,  $\overline{OE}$ ) to give designers the flexibility to prevent bus contention.

With 64K byte storage capability, the AT27C512R allows firmware to be stored reliably and to be accessed by the system without the delays of mass storage media.

The AT27C512R has additional features to ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the part and guarantees reliable programming. Programming time is typically only 100µs/byte. The integrated product identification code electronically identifies the device and manufacturer. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.



512K (64K x 8) One-time Programmable, Read-only Memory

Atmel AT27C512R







## 2. Pin configurations

Pin name	Function
A0 - A15	Addresses
00 - 07	Outputs
CE	Chip enable
0E/VPP	Output enable/ Program supply
NC	No connect



are don't connect

### 3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a  $0.1\mu$ F, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V<sub>CC</sub> and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a  $4.7\mu$ F bulk electrolytic capacitor should be utilized, again connected between the V<sub>CC</sub> and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.





### 4. Absolute maximum ratings\*

V <sub>PP</sub> supply voltage with respect to ground
Voltage on A9 with respect to ground2.0V to + 14.0V <sup>(1)</sup>
Voltage on any pin with respect to ground2.0V to + 7.0V <sup>(1)</sup>
Storage temperature65°C to + 150°C
Temperature under bias55°C to + 125°C

- \*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
- Note: 1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is  $V_{CC}$  + 0.75V DC, which may overshoot to +7.0V for pulses of less than 20ns.

## 5. DC and AC characteristics

Table 5-1.	Operating mode	25

Mode/Pin	CE	OE/V <sub>PP</sub>	Ai	Outputs
Read	V <sub>IL</sub>	V <sub>IL</sub>	Ai	D <sub>OUT</sub>
Output disable	V <sub>IL</sub>	V <sub>IH</sub>	X <sup>(1)</sup>	High Z
Standby	V <sub>IH</sub>	X <sup>(1)</sup>	X	High Z
Rapid program <sup>(2)</sup>	V <sub>IL</sub>	V <sub>PP</sub>	Ai	D <sub>IN</sub>
PGM inhibit	V <sub>IH</sub>	V <sub>PP</sub>	X <sup>(1)</sup>	High Z
Product identification <sup>(4)</sup>	V <sub>IL</sub>	V <sub>IL</sub>	$A9 = V_{H}^{(3)}$ $A0 = V_{H} \text{ or } V_{IL}$ $A1 - A15 = V_{IL}$	Identification code

Notes: 1. X can be  $V_{I\!L} \text{ or } V_{I\!H}$ 

2. Refer to programming characteristics.

- 3.  $V_{\rm H} = 12.0 \pm 0.5 V.$
- 4. Two identifier bytes may be selected. All Ai inputs are held low  $(V_{IL})$ , except A9, which is set to  $V_{H'}$  and A0, which is toggled low  $(V_{IL})$  to select the manufacturer's identification byte and high  $(V_{IH})$  to select the device code byte.

Table 5-2.	DC and AC operating conditions for read operation
Table J-Z.	De and Ae operating conditions for read operation

		Atmel AT27C512R		
		-45	-70	
	Ind.	-40°C - 85°C	-40°C - 85°C	
Operating temp. (case)	Auto.		-40°C - 125°C	
V <sub>CC</sub> supply		5V ± 10%	5V ± 10%	





Symbol	Parameter	Condition		Min	Max	Units
			Ind.		±1	μA
ILI	Input load current	rrent $V_{IN} = OV \text{ to } V_{CC}$	Auto.		±5	μA
			Ind.		±5	μA
ILO	Output leakage current	$V_{OUT} = 0V \text{ to } V_{CC}$ Auto.			±10	μA
		$I_{SB1}$ (CMOS), $\overline{CE} = V_{CC \pm} 0.3V$			100	μA
I <sub>SB</sub>	V <sub>CC</sub> <sup>(1)</sup> standby current	$I_{SB2}$ (TTL), $\overline{CE}$ = 2.0 to $V_{CC+}$ 0.5V			1	mA
I <sub>CC</sub>	V <sub>CC</sub> active current	$f = 5MHz, I_{OUT} = 0mA, \overline{CE} =$	$f = 5MHz$ , $I_{OUT} = 0mA$ , $\overline{CE} = V_{IL}$		20	mA
V <sub>IL</sub>	Input low voltage				0.8	V
V <sub>IH</sub>	Input high voltage			2.0	V <sub>CC</sub> + 0.5	V
V <sub>OL</sub>	Output low voltage	I <sub>OL</sub> = 2.1mA			0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -400μA		2.4		V

Table 5-3.DC and operating characteristics for read operation

Note: 1.  $V_{CC}$  must be applied simultaneously with or before  $\overline{OE}/V_{pp}$ , and removed simultaneously with or after  $\overline{OE}/V_{pp}$ .

Table 5-4. AC characteristics for read operation

				Atmel AT	27C512R	ł	
			-4	45		70	
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t <sub>ACC</sub> <sup>(1)</sup>	Address to output delay $\bar{C}$	$\overline{CE} = \overline{OE}/V_{PP} = V_{IL}$		45		70	ns
t <sub>CE</sub> <sup>(1)</sup>	CE to output delay C	$\overline{\text{DE}}/\text{V}_{\text{PP}} = \text{V}_{\text{IL}}$		45		70	ns
t <sub>OE</sub> <sup>(1)</sup>	$\overline{OE}/V_{PP}$ to output delay $\overline{C}$	$\overline{CE} = V_{IL}$		20		30	ns
t <sub>DF</sub> <sup>(1)</sup>	$\overline{\text{OE}}/\text{V}_{\text{PP}}$ or $\overline{\text{CE}}$ high to output float, which	ever occurred first		20		25	ns
t <sub>OH</sub>	Output hold from address, $\overline{CE}$ or $\overline{OE}/V_{pp}$ , whichever occurred first		7		7		ns

Note: 1. See AC waveforms for read operation.

Figure 5-1. AC waveforms for read operation<sup>(1)</sup>



- Notes: 1. Timing measurement reference level is 1.5V for -45 devices. Input AC drive levels are  $V_{IL} = 0.0V$  and  $V_{IH} = 3.0V$ . Timing measurement reference levels for all other speed grades are  $V_{OL} = 0.8V$  and  $V_{OH} = 2.0V$ . Input AC drive levels are  $V_{IL} = 0.45V$  and  $V_{IH} = 2.4V$ .
  - 2.  $\overline{OE}/V_{PP}$  may be delayed up to  $t_{CE}$   $t_{OE}$  after the falling edge of  $\overline{CE}$  without impact on  $t_{CE}$ .
  - 3.  $\overline{OE}/V_{PP}$  may be delayed up to  $t_{ACC}$   $t_{OE}$  after the address is valid without impact on  $t_{ACC}$ .
  - 4. This parameter is only sampled, and is not 100% tested.
  - 5. Output float is defined as the point when data is no longer driven.

Figure 5-2. Input test waveforms and measurement levels







Note: 1.  $C_L = 100 pF$  including jig capacitance, except for the -45 devices, where  $C_L = 30 pF$ .

Table 5-5.Pin capacitance

 $f = 1MHz, T = 25^{\circ}C^{(1)}$ 

Symbol	Тур	Мах	Units	Conditions
C <sub>IN</sub>	4	6	pF	$V_{IN} = OV$
C <sub>OUT</sub>	8	12	pF	$V_{OUT} = 0V$

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.



Figure 5-4. Programming Waveforms<sup>(1)</sup>

Notes: 1. The input timing reference is 0.8V for  $V_{\rm IL}$  and 2.0V for  $V_{\rm IH}$ 

2.  $t_{\text{OE}}$  and  $t_{\text{DFP}}$  are characteristics of the device, but must be accommodated by the programmer.

 Table 5-6.
 DC programming characteristics

 $\mathrm{T_A} = 25 \pm 5^{\mathrm{o}}\mathrm{C}, \, \mathrm{V_{CC}} = 6.5 \pm 0.25 \mathrm{V}, \, \overline{\mathrm{OE}}/\mathrm{V_{PP}} = 13.0 \pm 0.25 \mathrm{V}$ 

			Limits		
Symbol	Parameter	Test conditions	Min	Max	Units
ILI	Input load current	$V_{IN} = V_{IL}V_{IH}$		±10	μΑ
VIL	Input low level		-0.6	0.8	V
V <sub>IH</sub>	Input high level		2.0	V <sub>CC</sub> + 1	V
V <sub>OL</sub>	Output low voltage	$I_{OL} = 2.1 \text{mA}$		0.4	V
V <sub>OH</sub>	Output high voltage	I <sub>OH</sub> = -400μA	2.4		V
I <sub>CC2</sub>	V <sub>CC</sub> supply current (program and verify)			25	mA
I <sub>PP2</sub>	OE/V <sub>PP</sub> current	$\overline{CE} = V_{IL}$		25	mA
V <sub>ID</sub>	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_{A}$  = 25  $\pm$  5°C,  $V_{CC}$  = 6.5  $\pm$  0.25V,  $\overline{OE}/V_{PP}$  = 13.0  $\pm$  0.25V

			Lin	nits	
Symbol	Parameter	Test conditions <sup>(1)</sup>	Min	Max	Units
t <sub>AS</sub>	Address setup time		2		μs
t <sub>OES</sub>	$\overline{\text{OE}}/\text{V}_{\text{PP}}$ setup time		2		μs
t <sub>OEH</sub>	$\overline{\text{OE}}/\text{V}_{\text{PP}}$ hold time	Input rise and fall times	2		μs
t <sub>DS</sub>	Data setup time	(10% to 90%) 20ns	2		μs
t <sub>AH</sub>	Address hold time	Input pulse levels 0.45V to 2.4V Input timing reference level 0.8V to 2.0V	0		μs
t <sub>DH</sub>	Data hold time		2		μs
t <sub>DFP</sub>	CE high to output float delay <sup>(2)</sup>		0	130	ns
t <sub>VCS</sub>	V <sub>CC</sub> setup time		2		μs
t <sub>PW</sub>	CE program pulse width <sup>(3)</sup>		95	105	μs
t <sub>DV</sub>	Data valid from $\overline{CE}^{(2)}$	<ul><li>Output timing reference level</li><li>0.8V to 2.0V</li></ul>		1	μs
t <sub>VR</sub>	$\overline{\text{OE}}/\text{V}_{\text{PP}}$ recovery time		2		μs
t <sub>PRT</sub>	OE/V <sub>PP</sub> pulse rise time during programming		50		ns

Notes: 1.  $V_{CC}$  must be applied simultaneously with or before  $\overline{OE}/V_{PP}$  and removed simultaneously with or after  $\overline{OE}/V_{PP}$ .

2. This parameter is only sampled, and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.

3. Program pulse width tolerance is  $100\mu sec \pm 5\%$ .

Table 5-8.	The Atmel AT27C512R integrated product identification code
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		Pins								
Codes	A0	07	O6	O5	04	O3	02	01	00	Hex data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device type	1	0	0	0	0	1	1	0	1	0D



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## 6. Rapid programming algorithm

A 100µs  $\overline{CE}$  pulse width is used to program. The address is set to the first location.  $V_{CC}$  is raised to 6.5V and  $\overline{OE}/V_{PP}$  is raised to 13.0V. Each address is first programmed with one 100µs  $\overline{CE}$  pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100µs pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked.  $\overline{OE}/V_{PP}$  is then lowered to  $V_{IL}$  and  $V_{CC}$  to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.

Figure 6-1. Rapid programming algorithm



# 7. Ordering information

# Green package (Pb/halide-free)

t <sub>ACC</sub>	I <sub>CC</sub> (mA)					
(ns)	Active	Standby	Atmel ordering code	Package	Lead finish	Operation range
45	45 20	0.1	AT27C512R-45JU	32J	Matte tin	Industrial
45			AT27C512R-45PU	28P6	Matte tin	(-40°C to 85°C)
70	70 20	0.1	AT27C512R-70JU	32J	Matte tin	Industrial
70 20	0.1	AT27C512R-70PU	28P6	Matte tin	(-40°C to 85°C)	

Package type				
32J	32-lead, plastic, J-leaded chip carrier (PLCC)			
28P6	28-lead, 0.600" wide, plastic, dual inline package (PDIP)			





## 8. Packaging information

## 32J – PLCC



### 28P6 – PDIP







# 9. Revision history

Doc. rev.	Date	Comments
0015Q	10/2011	Correct pinout note
0015P	04/2011	Remove TSOP and SOIC packages Add lead finish to ordering information
00150	12/2007	



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